MOSFET

Metal Oxide Semiconductor Field Effect Transistor

CoolMOS™ CE

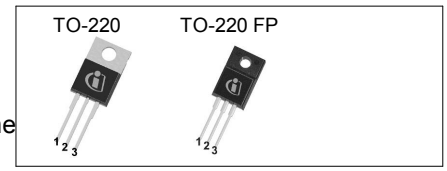
500V CoolMOS™ CE Power Transistor
IPx50R500CE

Data Sheet

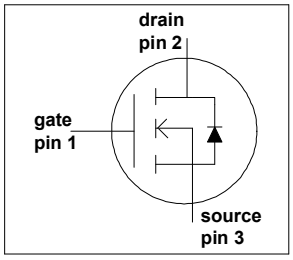
Rev. 2.0
Final

Industrial & Multimarket

1 Description



CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies. CoolMOS™ CE series combines the experience of the leading SJ MOSFET supplier with high class innovation while representing a cost appealing alternative compared to standard MOSFETs in target applications. The resulting devices provide all benefits of a fast switching SJ MOSFET while not sacrificing ease of use. Extremely low switching and conduction losses make switching applications even more efficient, more compact, lighter and cooler.



Features

- Extremely low losses due to very low FOM Rdson*Qg and Eoss
- Very high commutation ruggedness
- Easy to use/drive
- Pb-free plating, Halogen free mold compound
- Qualified for industrial grade applications according to JEDEC (J-STD20 and JESD22)

Applications

PFC stages, hard switching PWM stages and resonant switching PWM stages for e.g. PC Silverbox, LCD & PDP TV and Lighting.

Table 1 Key Performance Parameters

Parameter	Value	Unit
V_{DS} @ $T_{j,max}$	550	V
$R_{DS(on),max}$	0.5	Ω
$Q_{g.typ}$	18.7	nC
$I_{D,pulse}$	24	A
E_{oss}@400V	2.02	µJ
Body diode di/dt	500	A/µs

Type / Ordering Code	Package	Marking	Related Links
IPP50R500CE	PG-TO 220	5R500CE	see Appendix A
IPA50R500CE	PG-TO 220 FullPAK		

Table of Contents

2 Maximum ratings

at T_j = 25°C, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current[1]	I_D	- -	- -	7.6 4.8	A	T_C = 25°C T_C = 100°C
Pulsed drain current[2]	$I_{D,pulse}$	-	-	24	A	T_C=25°C
Avalanche energy, single pulse	E_{AS}	-	-	129	mJ	I_D =2.9A; V_{DD} = 50V
Avalanche energy, repetitive	E_{AR}	-	-	0.20	mJ	I_D =2.9A; V_{DD} = 50V
Avalanche current, repetitive	I_{AR}	-	-	2.9	A	-
MOSFET dv/dt ruggedness	dv/dt	-	-	50	V/ns	V_{DS} =0...400V
Gate source voltage	V_{GS}	-20 -30	- -	20 30	V	static; AC (f>1 Hz)
Power dissipation (non FullPAK) TO-220	P_{tot}	-	-	57	W	T_C=25°C
Power dissipation (FullPAK) TO-220FP	P_{tot}	-	-	28	W	T_C=25°C
Operating and storage temperature	T_j, T_{stg}	-55	-	150	°C	-
Mounting torque (non FullPAK) TO-220	-	-	-	60	Ncm	M3 and M3.5 screws
Mounting torque (FullPAK) TO-220FP	-	-	-	50	Ncm	M2.5 screws
Continuous diode forward current	I_S	-	-	6.6	A	T_C=25°C
Diode pulse current[2]	$I_{S,pulse}$	-	-	24.0	A	T_C = 25°C
Reverse diode dv/dt[3]	dv/dt	-	-	15	V/ns	V_{DS} =0...400V, I_{SD}<=I_S, T_j=25°C, t_{cond}<2µs
Maximum diode commutation speed[3]	di_f/dt	-	-	500	A/µs	V_{DS} =0...400V, I_{SD}<=I_S, T_j=25°C, t_{cond}<2µs
Insulation withstand voltage for TO-220 FullPAK	V_{ISO}	-	-	2500	V	V_{rms}, T_C=25°C, t=1min

3 Thermal characteristics

Table 3 Thermal characteristics (non FullPAK) TO-220

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	2.19	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	62	°C/W	leaded
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	1.6mm (0.063 in.) from case for 10s

[1] Limited by $T_{j\,max}$. Maximum duty cycle D=0.75
[2] Pulse width t_p limited by $T_{j,max}$
[3] V_{DClink}=400V; $V_{DS,peak}$< $V_{(BR)DSS}$; identical low side and high side switch with identical R_G

Table 4 Thermal characteristics (FullPAK) TO-220FP

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	4.46	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	80	°C/W	leaded
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	1.6mm (0.063 in.) from case for 10s

4 Electrical characteristics

Table 5 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	500	-	-	V	V_{GS}=0V, I_D=1mA
Gate threshold voltage	$V_{(GS)th}$	2.50	3	3.50	V	V_{DS}= V_{GS}, I_D=0.2mA
Zero gate voltage drain current	I_{DSS}	- -	- 10	1 -	µA	V_{DS}=500V, V_{GS}=0V, T_j=25°C V_{DS}=500V, V_{GS}=0V, T_j=150°C
Gate-source leakage curent	I_{GSS}	-	-	100	nA	V_{GS}=20V, V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	- -	0.45 1.18	0.50 -	Ω	V_{GS}=13V, I_D=2.3A, T_j=25°C V_{GS}=13V, I_D=2.3A, T_j=150°C
Gate resistance	R_G	-	3	-	Ω	f=1 MHz, open drain

Table 6 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	433	-	pF	V_{GS}=0V, V_{DS}=100V, f=1MHz
Output capacitance	C_{oss}	-	31	-	pF	V_{GS}=0V, V_{DS}=100V, f=1MHz
Effective output capacitance, energy related[1]	$C_{o(er)}$	-	25	-	pF	V_{GS}=0V, V_{DS}=0...400V
Effective output capacitance, time related[2]	$C_{o(tr)}$	-	100	-	pF	I_D=constant, V_{GS}=0V, V_{DS}=0...400V
Turn-on delay time	$t_{d(on)}$	-	6	-	ns	V_{DD}=400V, V_{GS}=13V, I_D=2.9A, R_G=3.4Ω
Rise time	t_r	-	5	-	ns	V_{DD}=400V, V_{GS}=13V, I_D=2.9A, R_G=3.4Ω
Turn-off delay time	$t_{d(off)}$	-	30	-	ns	V_{DD}=400V, V_{GS}=13V, I_D=2.9A, R_G=3.4Ω
Fall time	t_f	-	12	-	ns	V_{DD}=400V, V_{GS}=13 V, I_D=2.9A, R_G=3.4Ω

[1] $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$
[2] $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$

Table 7 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	2.3	-	nC	V_{DD}=400V, I_D=2.9A, V_{GS}=0 to 10V
Gate to drain charge	Q_{gd}	-	10	-	nC	V_{DD}=400V, I_D=2.9A, V_{GS}=0 to 10V
Gate charge total	Q_g	-	18.7	-	nC	V_{DD}=400V, I_D=2.9A, V_{GS}=0 to 10V
Gate plateau voltage	$V_{plateau}$	-	5.3	-	V	V_{DD}=400V, I_D=2.9A, V_{GS}=0 to 10V

Table 8 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}	-	0.85	-	V	V_{GS}=0V, I_F=2.9A, T_j=25°C
Reverse recovery time	t_{rr}	-	180	-	ns	V_R=400V, I_F=2.9A, di_F/dt=100A/µs
Reverse recovery charge	Q_{rr}	-	1.2	-	µC	V_R=400V, I_F=2.9A, di_F/dt=100A/µs
Peak reverse recovery current	I_{rrm}	-	12	-	A	V_R=400V, I_F=2.9A, di_F/dt=100A/µs

5 Electrical characteristics diagrams

Table 9

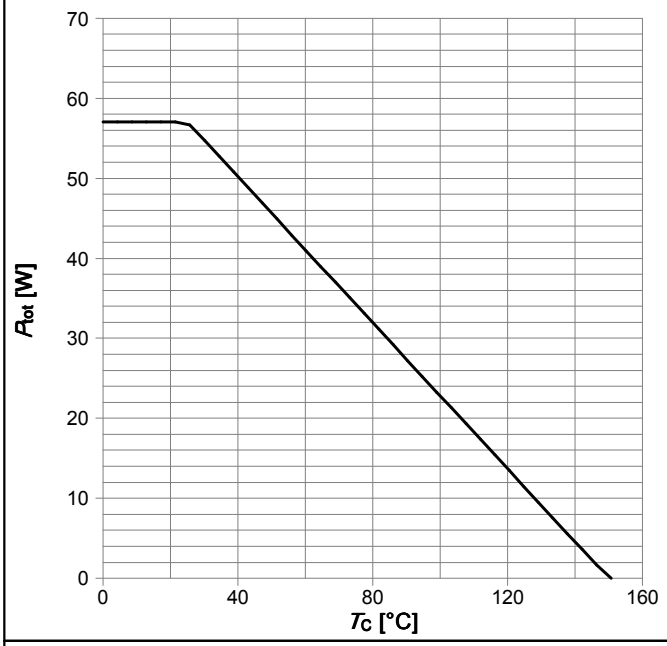
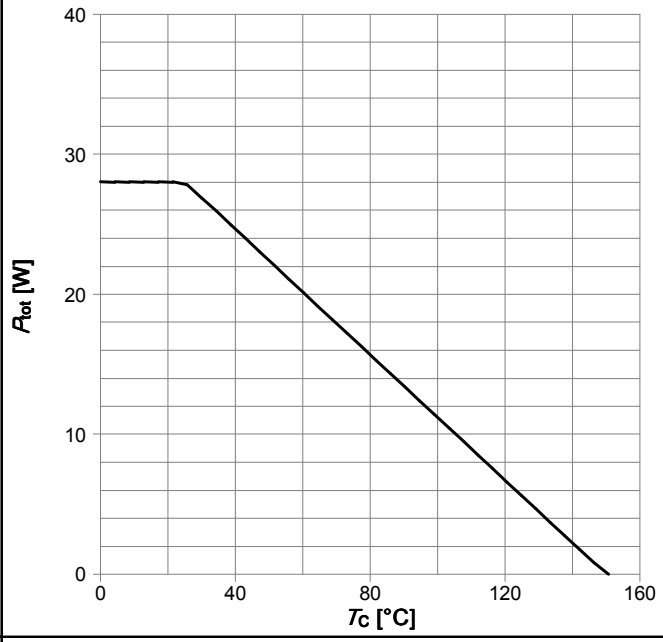
Power dissipation (Non FullPAK)	Power dissipation (FullPAK)
	
$P_{tot}=f(T_C)$	$P_{tot}=f(T_C)$

Table 10

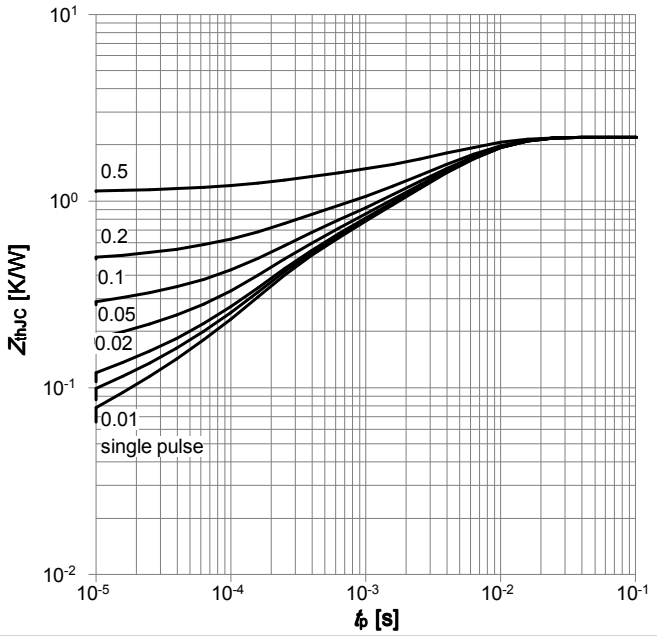
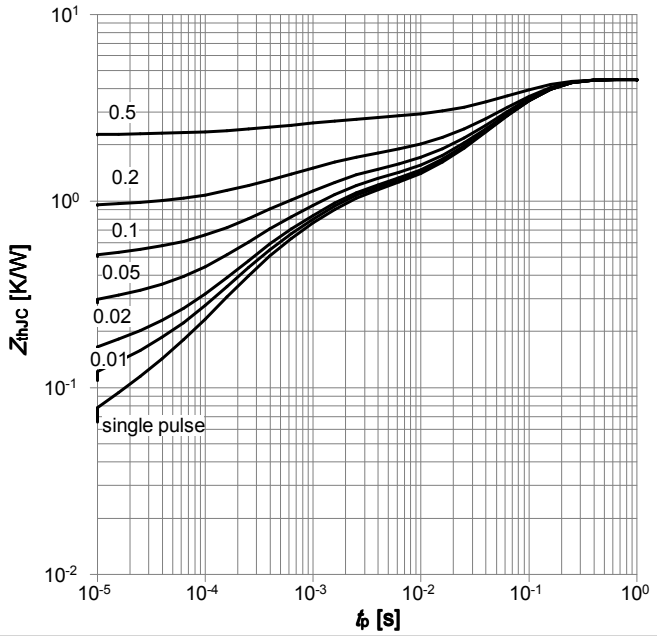
Max. transient thermal impedance (Non FullPAK)	Max. transient thermal impedance (FullPAK)
	
$Z_{thJC}=f(t_P)$; parameter: $D=t_p/T$	$Z_{thJC}=f(t_P)$; parameter: $D=t_p/T$

Table 11

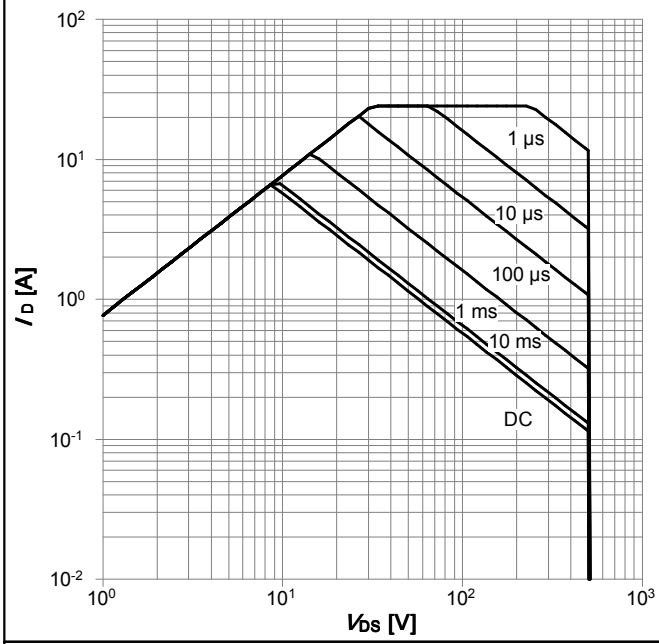
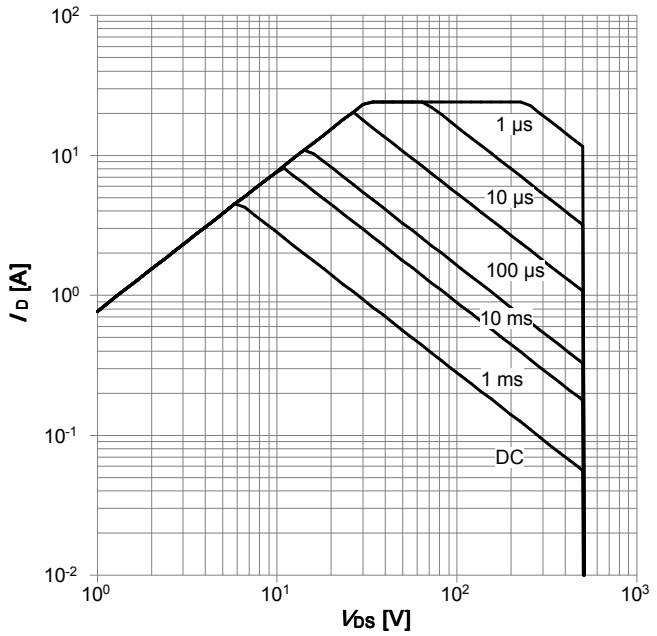
Safe operating area (Non FullPAK) Tj=25°C	Safe operating area (FullPAK) Tj=25°C
	
$I_D=f(V_{DS})$; $T_C=25$ °C; $D=0$; parameter: t_p	$I_D=f(V_{DS})$; $T_C=25$ °C; $D=0$; parameter: t_p

Table 12

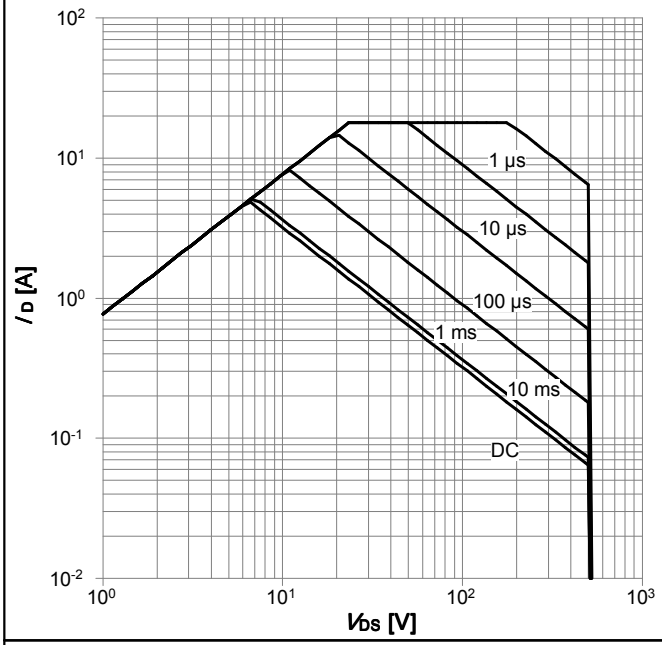
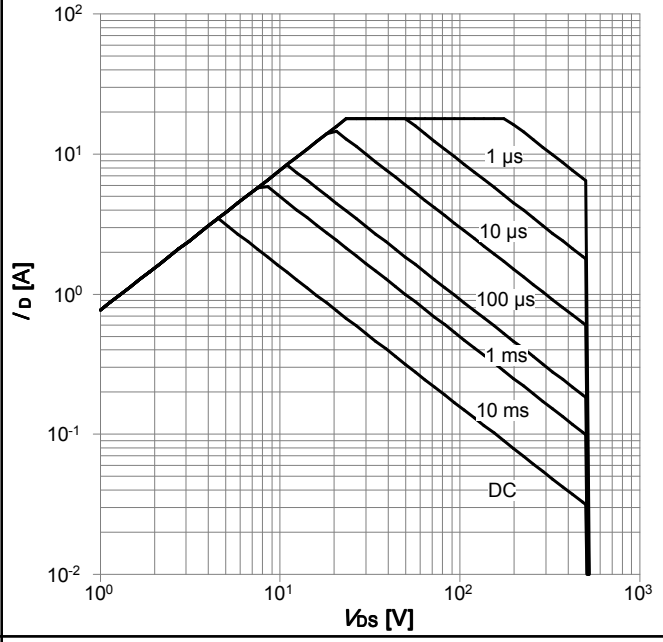
Safe operating area (Non FullPAK) Tj=80°C	Safe operating area (FullPAK) Tj=80°C
	
$I_D=f(V_{DS})$; $T_C=80$ °C; $D=0$; parameter: t_p	$I_D=f(V_{DS})$; $T_C=80$ °C; $D=0$; parameter: t_p

Table 13

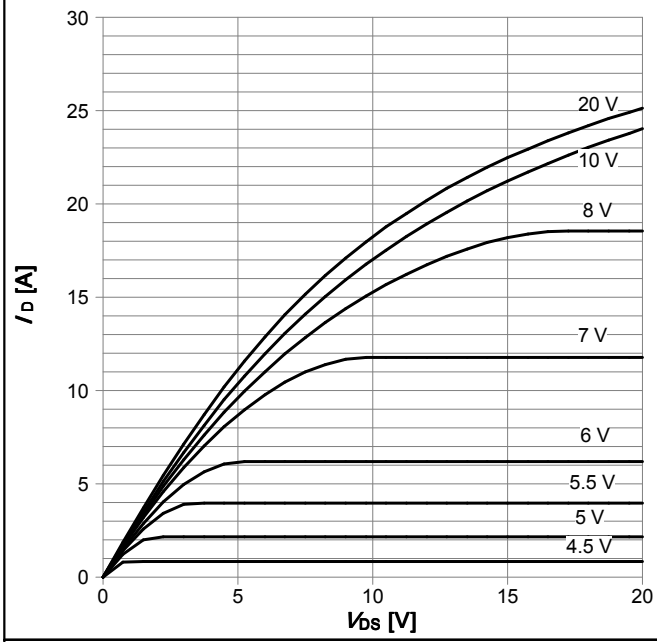
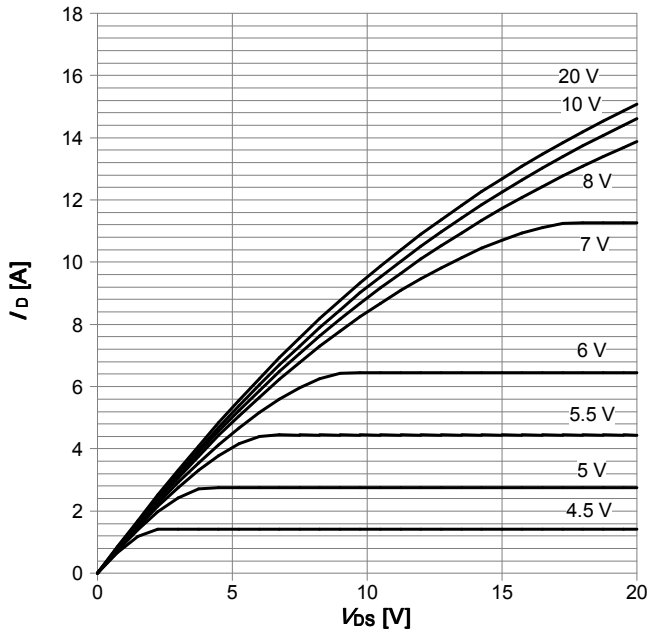
Typ. output characteristics Tj=25°C	Typ. output characteristics Tj=125°C
	
$I_D=f(V_{DS})$; T_j=25 °C; parameter: V_{GS}	$I_D=f(V_{DS})$; T_j=125 °C; parameter: V_{GS}

Table 14

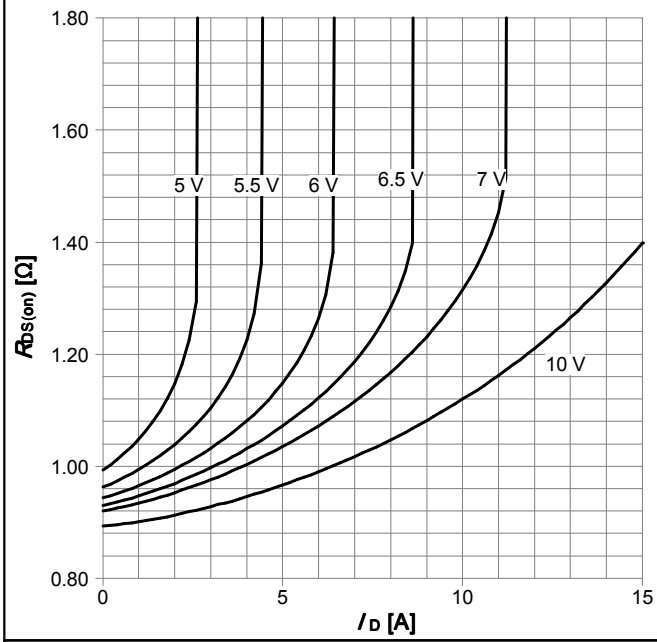
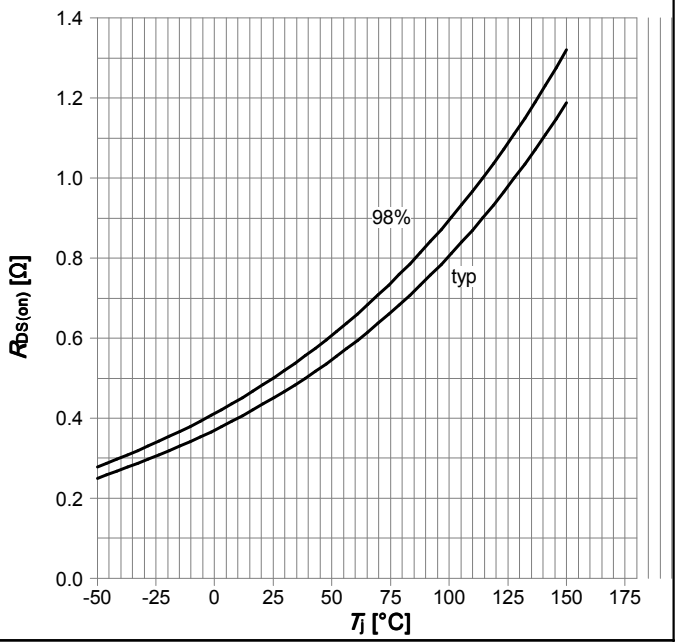
Typ. drain-source on-state resistance	Drain-source on-state resistance
	
$R_{DS(on)}=f(I_D)$; T_j=125 °C; parameter: V_{GS}	$R_{DS(on)}=f(T_j)$; I_D=2.3 A; V_{GS}=13 V

Table 15

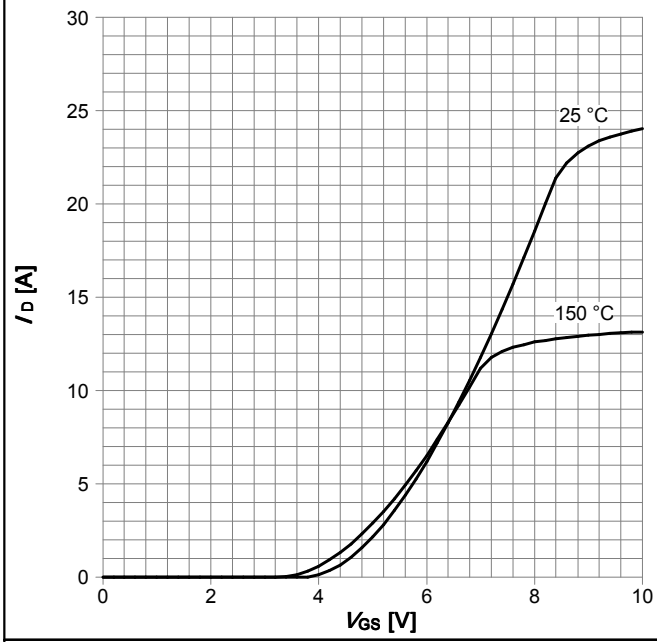
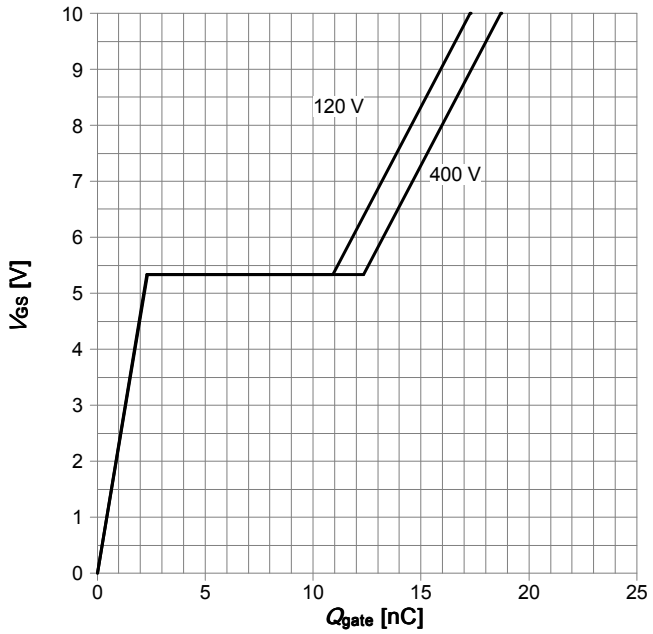
Typ. transfer characteristics	Typ. gate charge
	
I_D=f(V_{GS}); V_{DS}=20V; parameter: T_j	V_{GS}=f(Q_{gate}); I_D=2.9 A pulsed; parameter: V_{DD}

Table 16

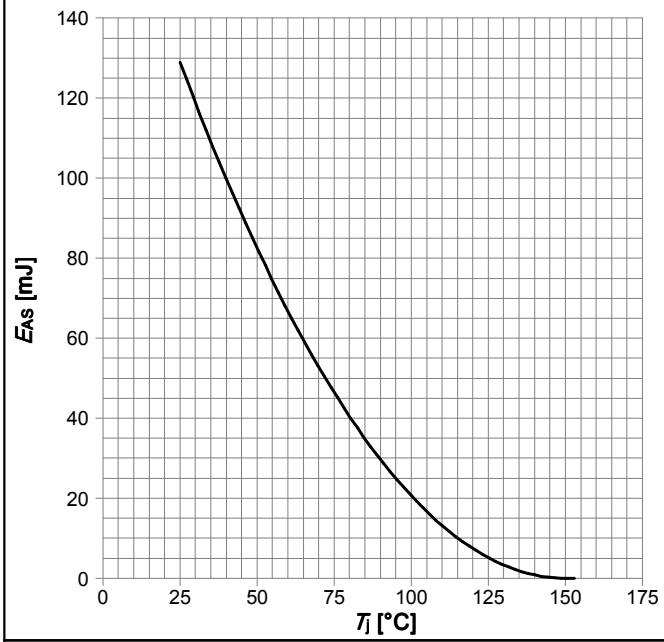
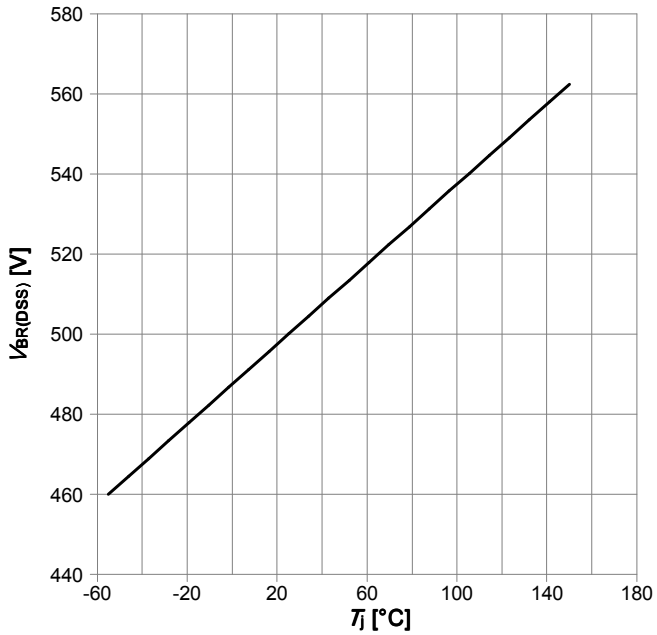
Avalanche energy	Drain-source breakdown voltage
	
E_{AS}=f(T_j); I_D=2.9 A; V_{DD}=50 V	$V_{BR(DSS)}$=f(T_j); I_D=1 mA

Table 17

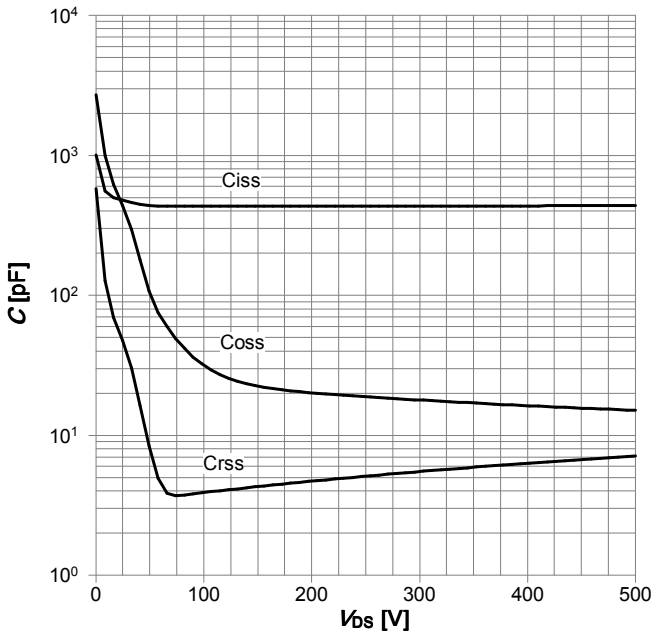
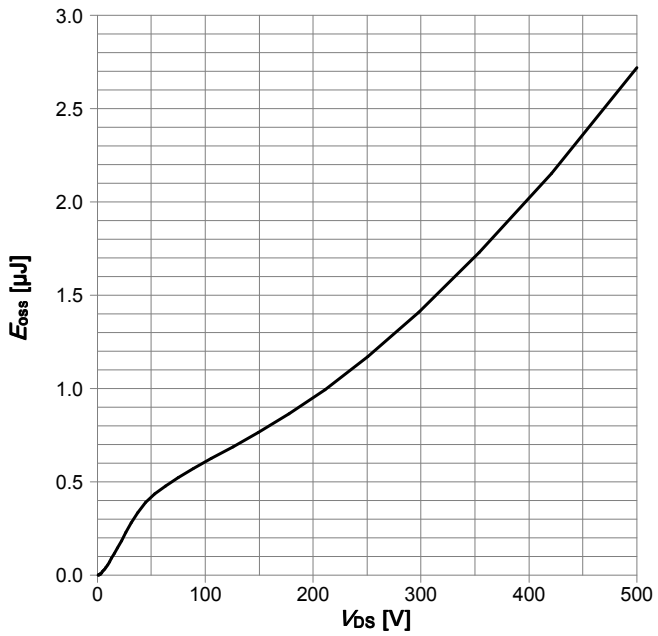
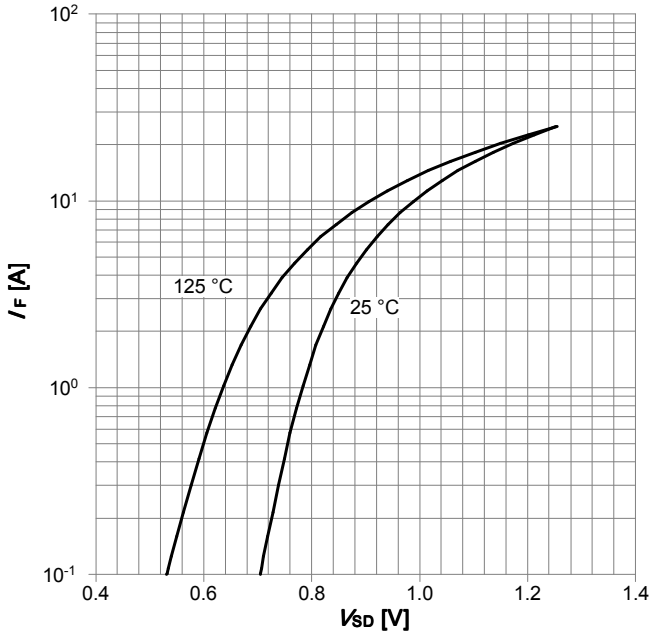
Typ. capacitances	Typ. Coss stored energy
	
C=f(V_{DS}); V_{GS}=0 V; f=1 MHz	E_{oss}=f(V_{DS})

Table 18

Forward characteristics of reverse diode

I_F=f(V_{SD}); parameter: T_j

6 Test Circuits

Table 19 Diode characteristics

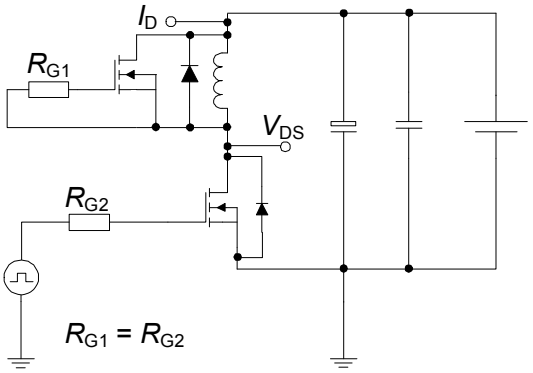
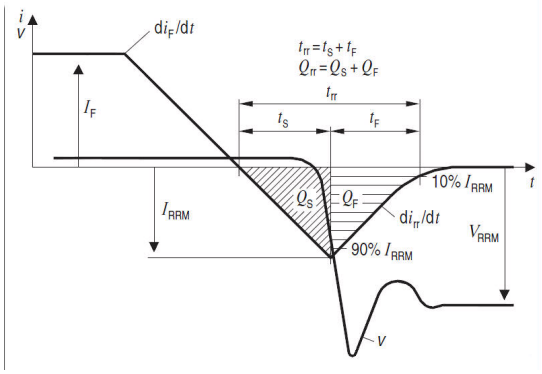
Test circuit for diode characteristics	Diode recovery waveform
	

Table 20 Switching times

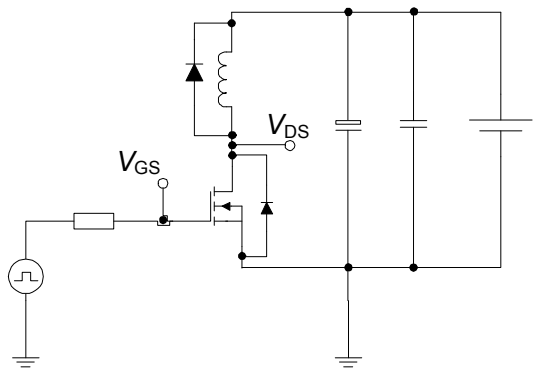
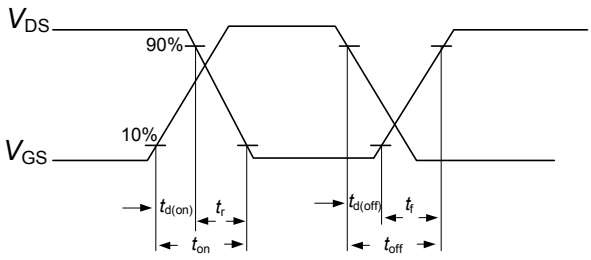
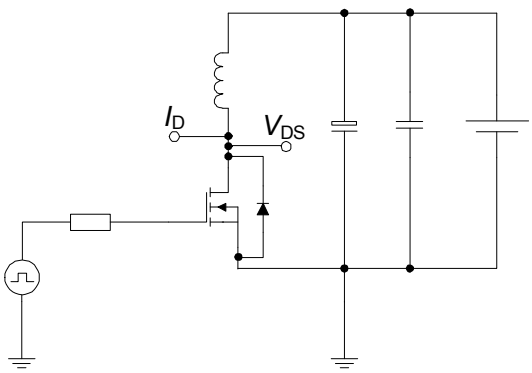
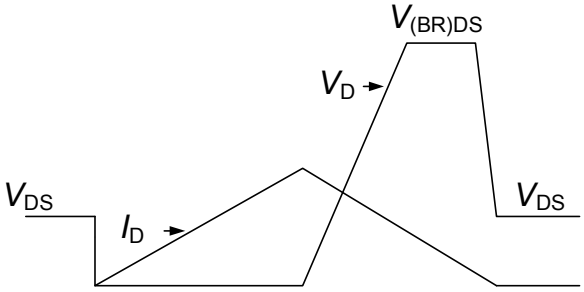
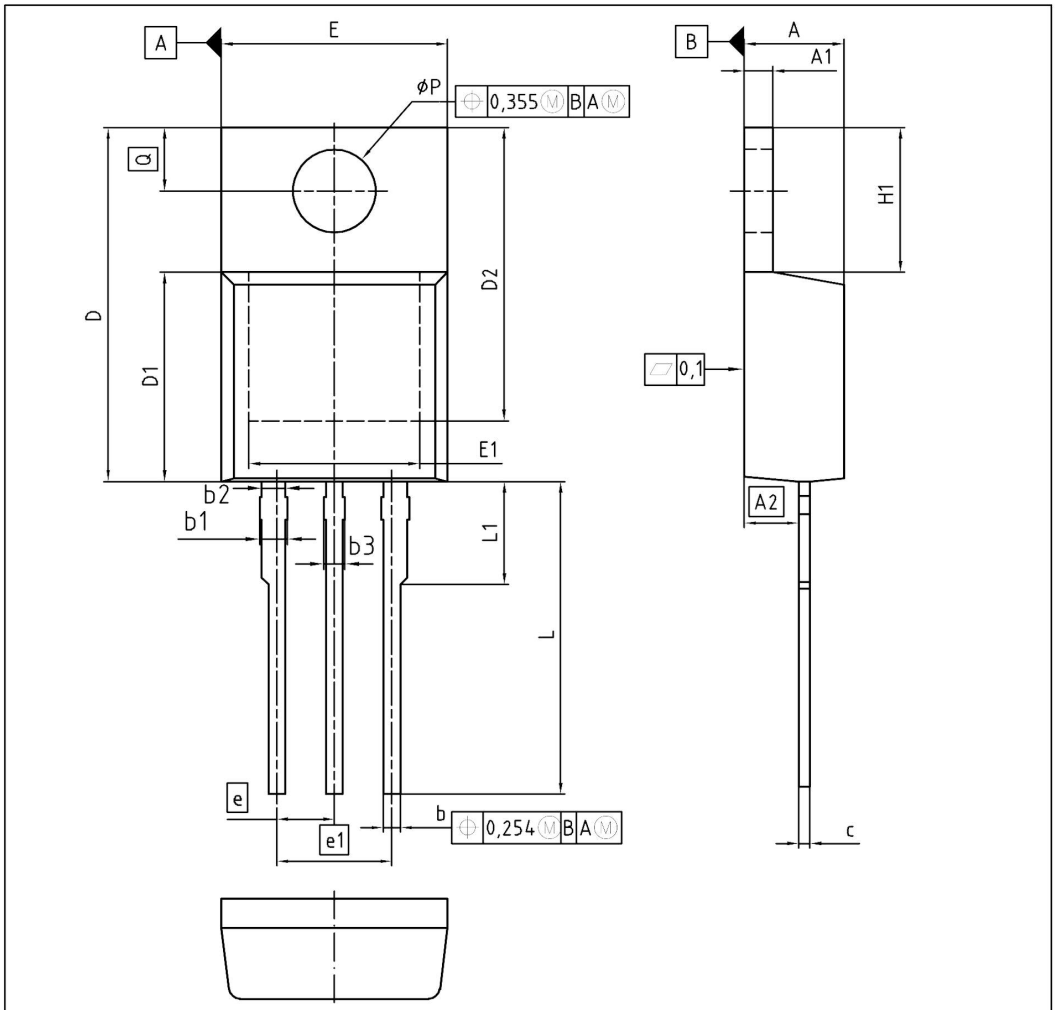
Switching times test circuit for inductive load	Switching times waveform
	

Table 21 Unclamped inductive

Unclamped inductive load test circuit	Unclamped inductive waveform
	

7 Package Outlines



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øP	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

DOCUMENT NO.
Z8B00003318

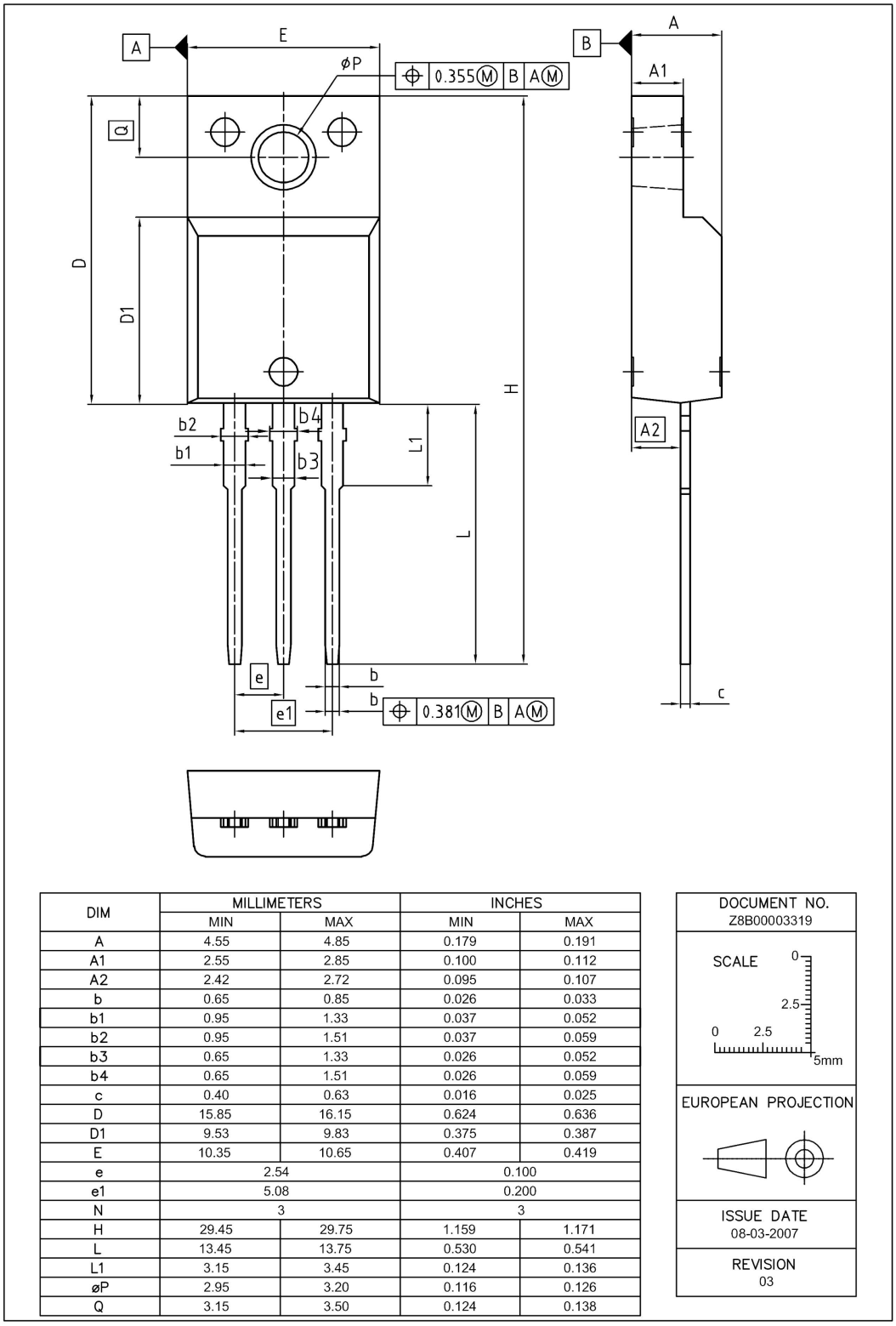
SCALE 0 2.5 0 2.5 5mm

EUROPEAN PROJECTION

ISSUE DATE
30-07-2009

REVISION
06

Figure 1 Outline PG-TO 220, dimensions in mm/inches



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.55	4.85	0.179	0.191
A1	2.55	2.85	0.100	0.112
A2	2.42	2.72	0.095	0.107
b	0.65	0.85	0.026	0.033
b1	0.95	1.33	0.037	0.052
b2	0.95	1.51	0.037	0.059
b3	0.65	1.33	0.026	0.052
b4	0.65	1.51	0.026	0.059
c	0.40	0.63	0.016	0.025
D	15.85	16.15	0.624	0.636
D1	9.53	9.83	0.375	0.387
E	10.35	10.65	0.407	0.419
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H	29.45	29.75	1.159	1.171
L	13.45	13.75	0.530	0.541
L1	3.15	3.45	0.124	0.136
øP	2.95	3.20	0.116	0.126
Q	3.15	3.50	0.124	0.138

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SCALE 0 2.5 0 2.5 5mm

EUROPEAN PROJECTION

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03

Figure 2 Outline PG-TO 220 FullPAK, dimensions in mm/inches

8 Appendix A

Table 22 Related Links

- **IFX CoolMOS Webpage:**
  http://www.infineon.com/cms/en/product/channel.html?channel=ff80808112ab681d0112ab6a628704d8
- **IFX Design tools:**
  http://www.infineon.com/cms/en/product/promopages/designtools/index.html

Revision History

IPP50R500CE, IPA50R500CE

Revision: 2012-06-28, Rev. 2.0

Previous Revision		
Revision	Date	Subjects (major changes since last revision)
2.0	2012-06-28	Release of final version

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